

## Pm39LV512 / Pm39LV010 / Pm39LV020 / Pm39LV040 512 Kbit / 1Mbit / 2Mbit / 4Mbit 3.0 Volt-only CMOS Flash Memory

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### FEATURES

- **Single Power Supply Operation**
    - Low voltage range: 2.7 V - 3.6 V
  - **Memory Organization**
    - Pm39LV512: 64K x 8 (512 Kbit)
    - Pm39LV010: 128K x 8 (1 Mbit)
    - Pm39LV020: 256K x 8 (2 Mbit)
    - Pm39LV040: 512K x 8 (4 Mbit)
  - **High Performance Read**
    - 55/70 ns access time
  - **Cost Effective Sector/Block Architecture**
    - Uniform 4 Kbyte sectors
    - Uniform 64 Kbyte blocks (sector group - except Pm39LV512)
  - **Data# Polling and Toggle Bit Features**
  - **Hardware Data Protection**
  - **Automatic Erase and Byte Program**
    - Build-in automatic program verification
    - Typical 16  $\mu$ s/byte programming time
    - Typical 55 ms sector/block/chip erase time
  - **Low Power Consumption**
    - Typical 4 mA active read current
    - Typical 8 mA program/erase current
    - Typical 0.1  $\mu$ A CMOS standby current
  - **High Product Endurance**
    - Guarantee 100,000 program/erase cycles per single sector (preliminary)
    - Minimum 20 years data retention
  - **Industrial Standard Pin-out and Packaging**
    - 32-pin (8 mm x 14 mm) VSOP
    - 32-pin PLCC
    - Optional lead-free (Pb-free) package
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### GENERAL DESCRIPTION

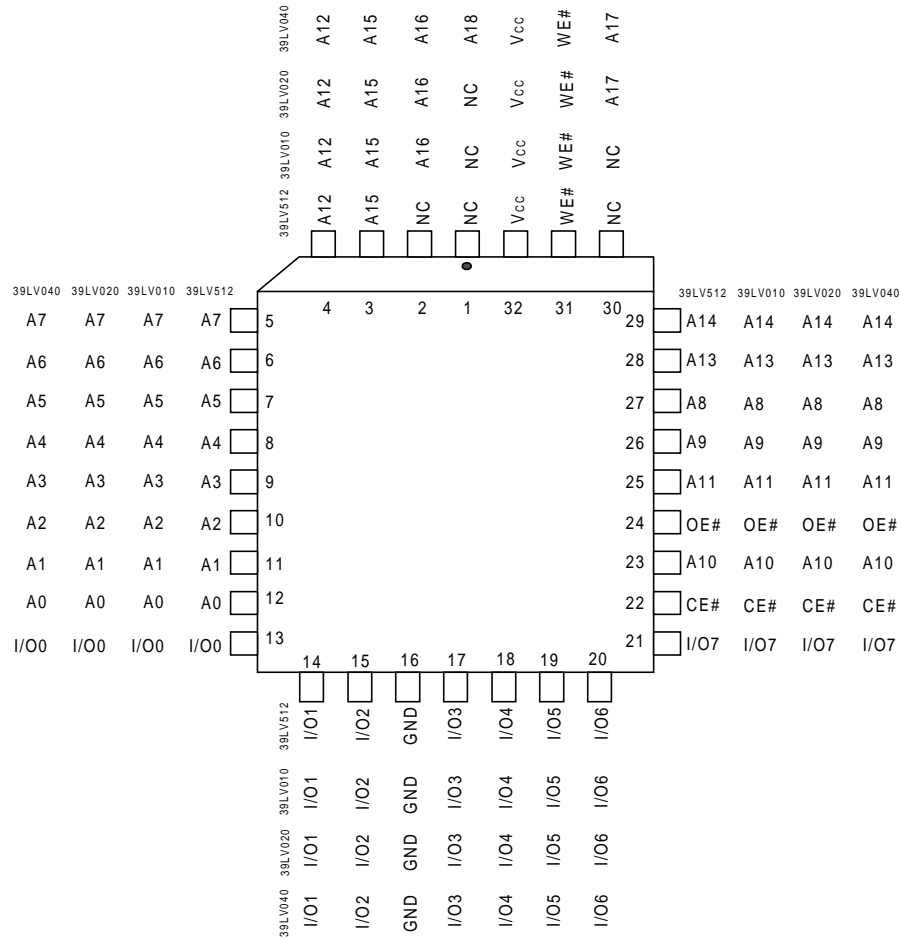
The Pm39LV512/010/020/040 are 512 Kbit/1 Mbit/2 Mbit/4 Mbit 3.0 Volt-only Flash Memories. These devices are designed to use a single low voltage, range from 2.7 Volt to 3.6 Volt, power supply to perform read, erase and program operations. The 12.0 Volt  $V_{pp}$  power supply for program and erase operations are not required. The devices can be programmed in standard EPROM programmers as well.

The memory array of Pm39LV512 is divided into uniform 4 Kbyte sectors for data or code storage. The memory arrays of Pm39LV010/020/040 are divided into uniform 4 Kbyte sectors or uniform 64 Kbyte blocks (sector group - consists of sixteen adjacent sectors). The sector or block erase feature allows users to flexibly erase a memory area as small as 4 Kbyte or as large as 64 Kbyte by one single erase operation without affecting the data in others. The chip erase feature allows the whole memory array to be erased in one single erase operation. The devices can be programmed on a byte-by-byte basis after performing the erase operation.

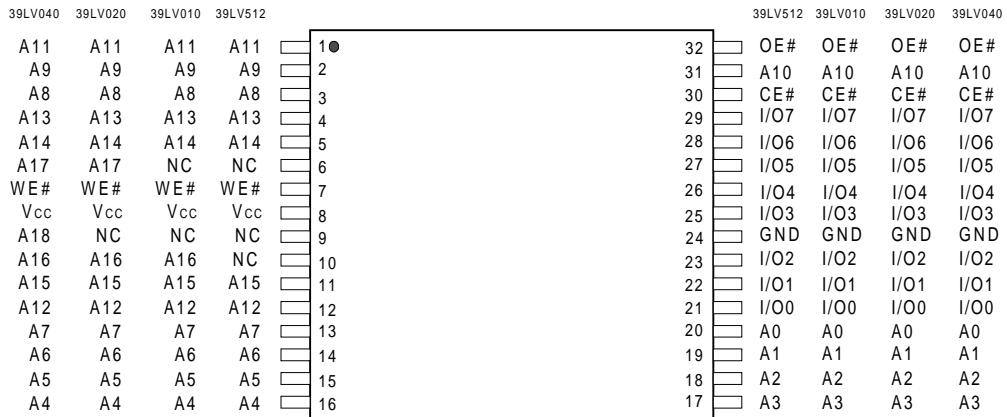
The devices have a standard microprocessor interface as well as a JEDEC standard pin-out/command set. The program operation is executed by issuing the program command code into command register. The internal control logic automatically handles the programming voltage ramp-up and timing. The erase operation is executed by issuing the chip erase, block, or sector erase command code into command register. The internal control logic automatically handles the erase voltage ramp-up and timing. The preprogramming on the array which has not been programmed is not required before an erase operation. The devices offer Data# Polling and Toggle Bit functions, the progress or completion of program and erase operations can be detected by reading the Data# Polling on I/O7 or the Toggle Bit on I/O6.

The Pm39LV512/010/020/040 are manufactured on pFLASH™'s advanced nonvolatile CMOS technology. The devices are offered in 32-pin VSOP and PLCC packages with 70 ns access time.

**CONNECTION DIAGRAMS**

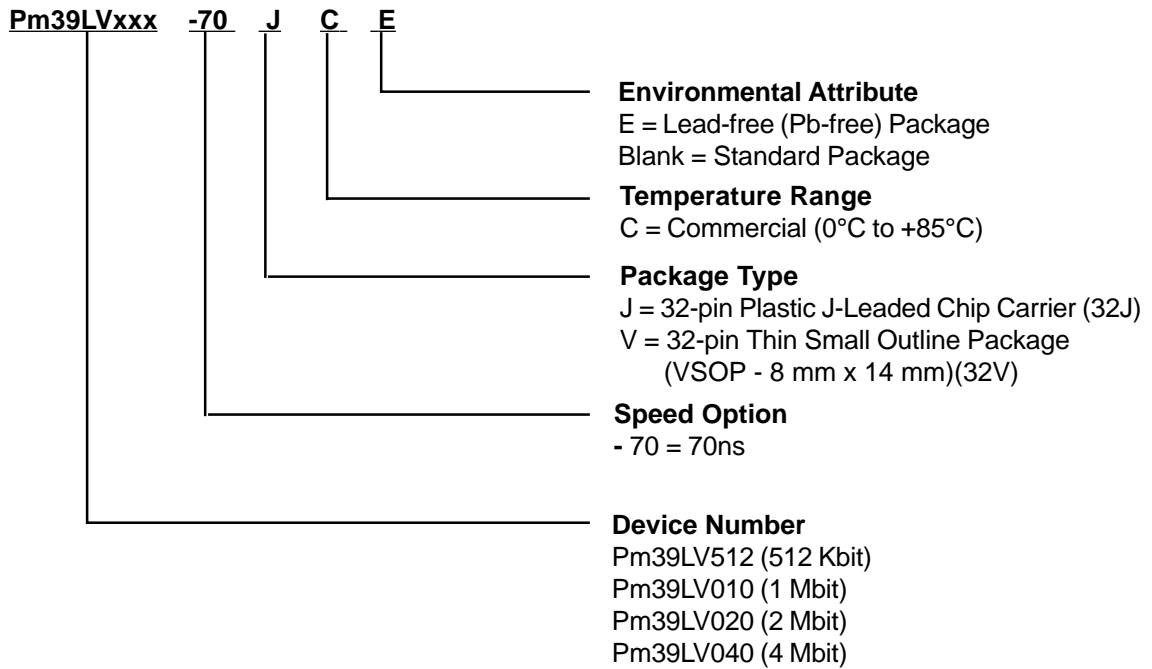


**32-Pin PLCC**



**32-Pin VSOP**

**PRODUCT ORDERING INFORMATION**



Part Number	t <sub>acc</sub> (ns)	Package	Temperature Range
Pm39LV512-70JCE	70	32J	Commercial (0°C to +85°C)
Pm39LV512-70JC			
Pm39LV512-70VCE		32V	
Pm39LV512-70VC			
Pm39LV010-70JCE	70	32J	
Pm39LV010-70JC			
Pm39LV010-70VCE		32V	
Pm39LV010-70VC			
Pm39LV020-70JCE	70	32J	
Pm39LV020-70JC			
Pm39LV020-70VCE		32V	
Pm39LV020-70VC			
Pm39LV040-70JCE	70	32J	
Pm39LV040-70JC			
Pm39LV040-70VCE		32V	
Pm39LV040-70VC			

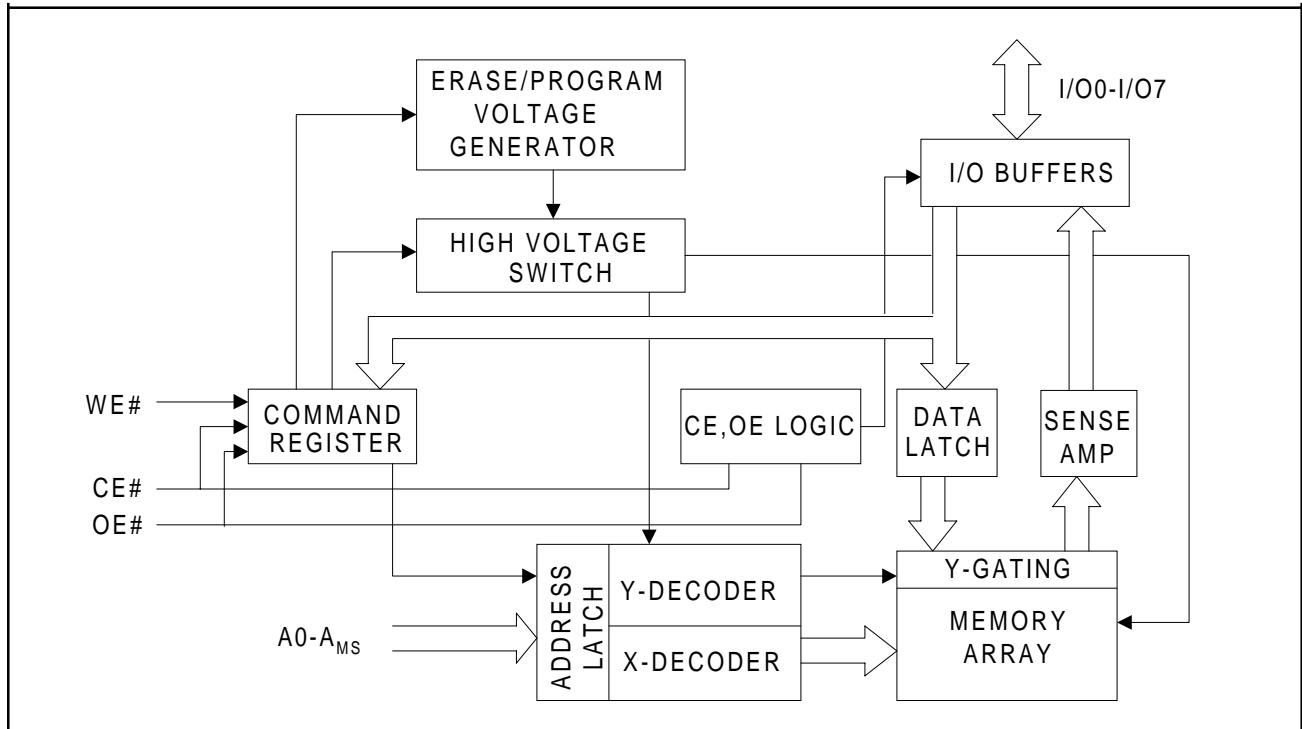
**PIN DESCRIPTIONS**

SYMBOL	TYPE	DESCRIPTION
A0 - A <sub>MS</sub> <sup>(1)</sup>	INPUT	Address Inputs: For memory addresses input. Addresses are internally latched on the falling edge of WE# during a write cycle.
CE#	INPUT	Chip Enable: CE# goes low activates the device's internal circuitries for device operation. CE# goes high deselects the device and switches into standby mode to reduce the power consumption.
WE#	INPUT	Write Enable: Activate the device for write operation. WE# is active low.
OE#	INPUT	Output Enable: Control the device's output buffers during a read cycle. OE# is active low.
I/O0 - I/O7	INPUT/ OUTPUT	Data Inputs/Outputs: Input command/data during a write cycle or output data during a read cycle. The I/O pins float to tri-state when OE# are disabled.
V <sub>CC</sub>		Device Power Supply
GND		Ground
NC		No Connection

**Note:**

1. A<sub>MS</sub> is the most significant address where A<sub>MS</sub> = A15 for Pm39LV512, A16 for Pm39LV010, A17 for Pm39LV020, and A18 for Pm39LV040.

## **BLOCK DIAGRAM**



## **DEVICE OPERATION**

### **READ OPERATION**

The access of Pm39LV512/010/020/040 are similar to EPROM. To read data, three control functions must be satisfied:

- CE# is the chip enable and should be pulled low ( $V_{IL}$ ).
- OE# is the output enable and should be pulled low ( $V_{IL}$ ).
- WE# is the write enable and should remain high ( $V_{IH}$ ).

### **PRODUCT IDENTIFICATION**

The product identification mode can be used to identify the manufacturer and the device through hardware or software read ID operation. See Table 1 for pFLASH™ Manufacturer ID and Device ID. The hardware ID mode is activated by applying a 12.0 Volt on A9 pin, typically used by an external programmer for selecting the right programming algorithm for the devices. Refer to Table 2 for Bus Operation Modes. The software ID mode is activated by a three-bus-cycle command. See Table 3 for Software Command Definition.

### **BYTE PROGRAMMING**

The programming is a four-bus-cycle operation and the data is programmed into the devices (to a logical "0") on a byte-by-byte basis. See Table 3 for Software Command Definition. A program operation is activated by writing the three-byte command sequence followed by program address and one byte of program data into the devices. The addresses are latched on the falling edge of WE# or CE# whichever occurs later, and the data are latched on the rising edge of WE# or CE# whichever occurs first. The internal control logic automatically handles the internal programming voltages and timing.

A data "0" can not be programmed back to a "1". Only erase operation can convert the "0"s to "1"s. The Data# Polling on I/O7 or Toggle Bit on I/O6 can be used to detect the progress or completion of a program cycle.

## **DEVICE OPERATION (CONTINUED)**

### **CHIP ERASE**

The entire memory array can be erased through a chip erase operation. Pre-programs the devices are not required prior to a chip erase operation. Chip erase starts immediately after a six-bus-cycle chip erase command sequence. All commands will be ignored once the chip erase operation has started. The devices will return to standby mode after the completion of chip erase.

### **SECTOR AND BLOCK ERASE**

The memory array of Pm39LV512/010/020/040 are organized into uniform 4 Kbyte sectors. A sector erase operation allows to erase any individual sector without affecting the data in others. The memory array of Pm39LV010/020/040, excluding Pm39LV512, are also organized into uniform 64 Kbyte blocks (sector group - consists of sixteen adjacent sectors). A block erase operation allows to erase any individual block. The sector or block erase operation is similar to chip erase.

### **I/O7 DATA# POLLING**

The Pm39LV512/010/020/040 provide a Data# Polling feature to indicate the progress or completion of a program and erase cycles. During a program cycle, an attempt to read the devices will result in the complement of the last loaded data on I/O7. Once the program operation is completed, the true data of the last loaded data is valid on all outputs. During a sector, block, or chip erase cycle, an attempt to read the device will result a "0" on I/O7. After the erase operation is completed, an attempt to read the device will result a "1" on I/O7.

### **I/O6 TOGGLE BIT**

The Pm39LV512/010/020/040 also provide a Toggle Bit feature to detect the progress or completion of a program and erase cycles. During a program or erase cycle, an attempt to read data from the device will result a toggling between "1" and "0" on I/O6. When the program or erase operation is complete, I/O6 will stop toggling and valid data will be read. Toggle bit may be accessed at any time during a program or erase cycle.

### **HARDWARE DATA PROTECTION**

Hardware data protection protects the devices from unintentional erase or program operation. It is performed in the following ways: (a)  $V_{CC}$  sense: if  $V_{CC}$  is below 1.8 V (typical), the write operation is inhibited. (b) Write inhibit: holding any of the signal OE# low, CE# high, or WE# high inhibits a write cycle. (c) Noise filter: pulses of less than 5 ns (typical) on the WE# or CE# input will not initiate a write operation.

**Table 1. Product Identification**

<b>Product Identification</b>	<b>Data</b>
Manufacturer ID	9Dh
Device ID:	
Pm39LV512	1Bh
Pm39LV010	1Ch
Pm39LV020	3Dh
Pm39LV040	3Eh

**SECTOR/BLOCK ADDRESS TABLE**

Memory Density				Block <sup>(1)</sup>	Block Size (Kbytes)	Sector	Sector Size (Kbytes)	Address Range		
512Kbit	1 Mbit	2 Mbit	4 Mbit	Block 0 <sup>(2)</sup>	64	Sector 0	4	00000h - 00FFFh		
						Sector 1	4	01000h - 01FFFh		
:	:	:								
Sector 15	4	0F000h - 0FFFFh								
				Block 1	64	Sector 16	4	10000h - 10FFFh		
						Sector 17	4	11000h - 11FFFh		
:	:	:								
Sector 31	4	1F000h - 1FFFFh								
						Block 2	64	"	"	20000h - 2FFFFh
						Block 3	64	"	"	30000h - 3FFFFh
						Block 4	64	"	"	40000h - 4FFFFh
						Block 5	64	"	"	50000h - 5FFFFh
				Block 6	64	"	"	60000h - 6FFFFh		
				Block 7	64	"	"	70000h - 7FFFFh		

## Notes:

1. A Block is a 64 Kbyte sector group which consists of sixteen adjacent sectors of 4 Kbyte each.
2. Block erase feature is available for Pm39LV010/020/040 only. The chip erase command should be used to erase the Block 0 for the Pm39LV512.

## OPERATING MODES

**Table 2. Bus Operation Modes**

Mode	CE#	OE#	WE#	ADDRESS	I/O
Read	V <sub>IL</sub>	V <sub>L</sub>	V <sub>IH</sub>	X <sup>(1)</sup>	D <sub>OUT</sub>
Write	V <sub>IL</sub>	V <sub>IH</sub>	V <sub>L</sub>	X	D <sub>IN</sub>
Standby	V <sub>IH</sub>	X	X	X	High Z
Output Disable	X	V <sub>IH</sub>	X	X	High Z
Product Identification Hardware	V <sub>L</sub>	V <sub>L</sub>	V <sub>IH</sub>	A2 - A <sub>MS</sub> <sup>(2)</sup> = X, A9 = V <sub>H</sub> <sup>(3)</sup> , A1 = V <sub>L</sub> , A0 = V <sub>L</sub>	Manufacturer ID
				A2 - A <sub>MS</sub> <sup>(2)</sup> = X, A9 = V <sub>H</sub> <sup>(3)</sup> , A1 = V <sub>L</sub> , A0 = V <sub>IH</sub>	Device ID

Notes:

- X can be V<sub>IL</sub>, V<sub>IH</sub> or addresses.
- A<sub>MS</sub> = Most significant address;  
A<sub>MS</sub> = A15 for Pm39LV512, A16 for Pm39LV010,  
A17 for Pm39LV020, and A18 for Pm39LV040.
- V<sub>H</sub> = 12.0 V ± 0.5 V.

## COMMAND DEFINITION

**Table 3. Software Command Definition**

Command Sequence	Bus Cycle	1st Bus Cycle Addr Data	2nd Bus Cycle Addr Data	3rd Bus Cycle Addr Data	4th Bus Cycle Addr Data	5th Bus Cycle Addr Data	6th Bus Cycle Addr Data
Read	1	Addr D <sub>OUT</sub>					
Chip Erase	6	555h AAh	2AAh 55h	555h 80h	555h AAh	2AAh 55h	555h 10h
Sector Erase	6	555h AAh	2AAh 55h	555h 80h	555h AAh	2AAh 55h	SA <sup>(1)</sup> 30h
Block Erase	6	555h AAh	2AAh 55h	555h 80h	555h AAh	2AAh 55h	BA <sup>(2)</sup> 50h
Byte Program	4	555h AAh	2AAh 55h	555h A0h	Addr D <sub>N</sub>		
Product ID Entry	3	555h AAh	2AAh 55h	555h 90h			
Product ID Exit <sup>(3)</sup>	3	555h AAh	2AAh 55h	555h F0h			
Product ID Exit <sup>(3)</sup>	1	XXXh F0h					

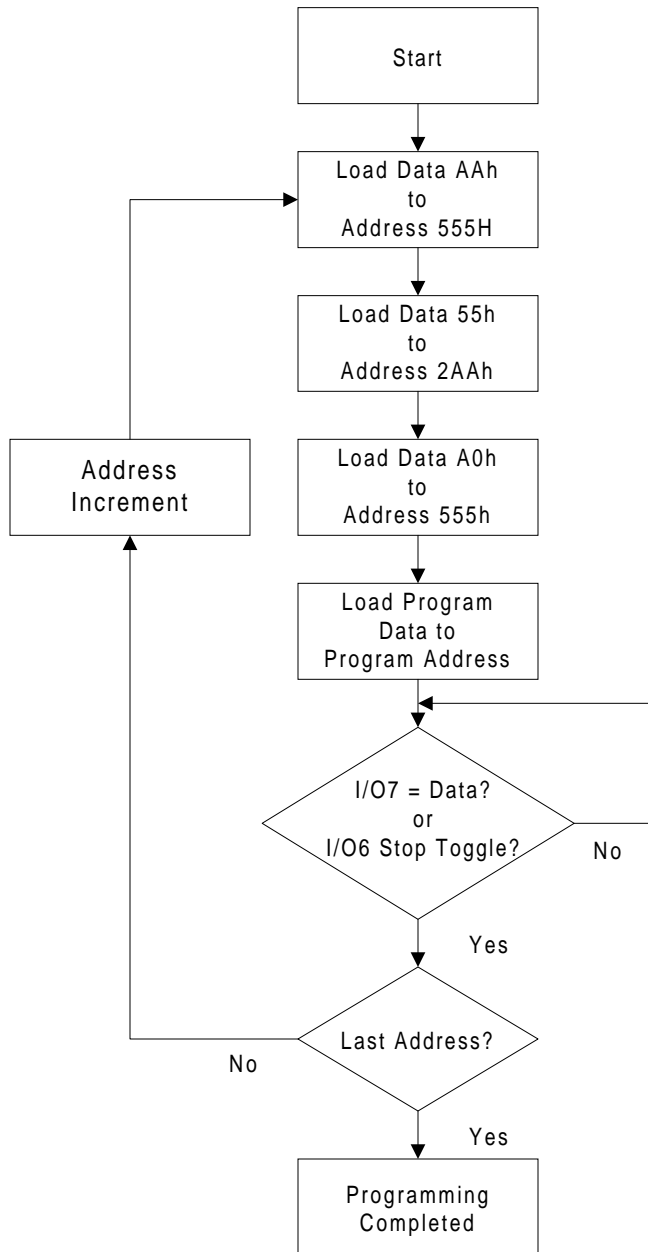
Notes:

- SA = Sector address of the sector to be erased.
- BA = Block address of the block to be erased.
- Either one of the Product ID Exit command can be used.



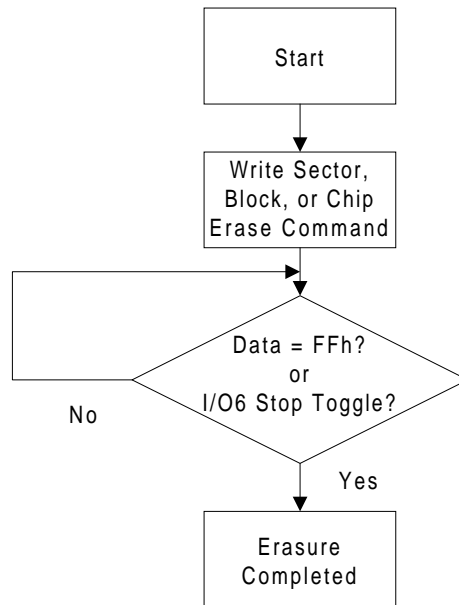
**DEVICE OPERATIONS FLOWCHARTS**

**AUTOMATIC PROGRAMMING**

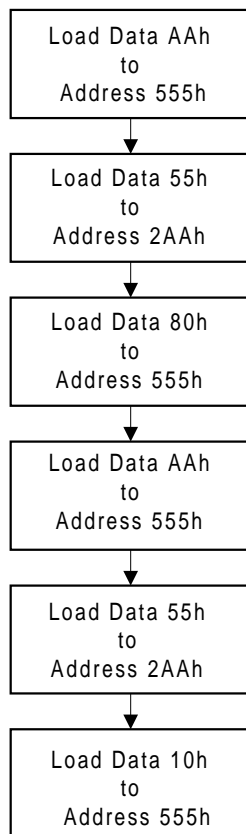


**Chart 1. Automatic Programming Flowchart**

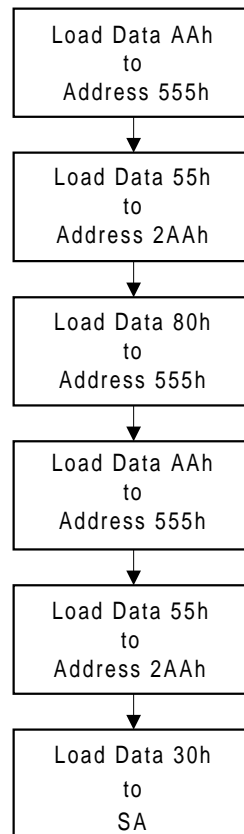
**DEVICE OPERATIONS FLOWCHARTS  
(CONTINUED)  
AUTOMATIC ERASE**



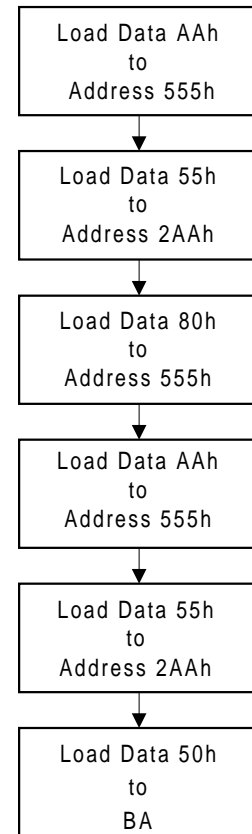
**CHIP ERASE COMMAND**



**SECTOR ERASE COMMAND**



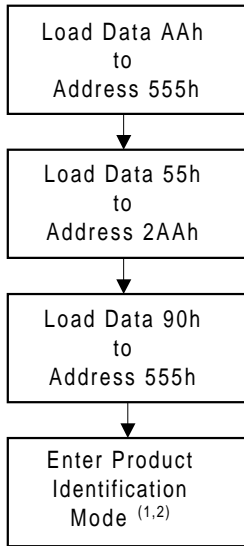
**BLOCK ERASE COMMAND**



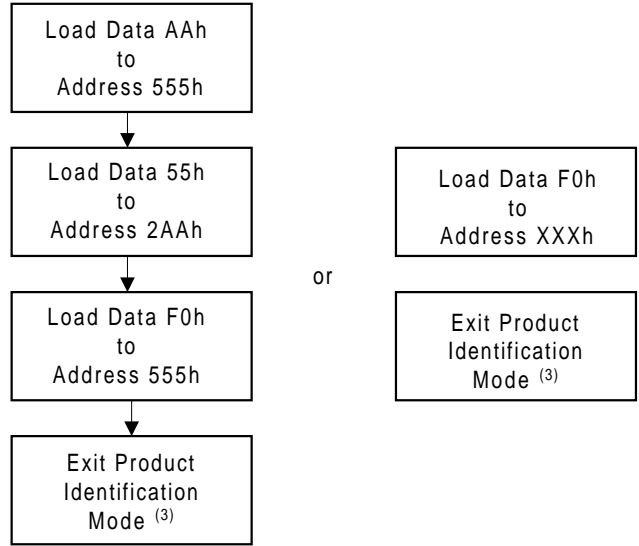
**Chart 2. Automatic Erase Flowchart**

**DEVICE OPERATIONS FLOWCHARTS  
(CONTINUED)**

**SOFTWARE PRODUCT IDENTIFICATION ENTRY**



**SOFTWARE PRODUCT IDENTIFICATION EXIT**



**Notes:**

1. The device will enter Product Identification mode after executing the Product ID Entry command.
2. Under Product Identification mode, the Manufacturer ID and Device ID of devices can be read at address X0000h and X0001h where X = Don't Care.
3. The device returns to standby operation.

**Chart 3. Software Product Identification Entry/Exit Flowchart**

**ABSOLUTE MAXIMUM RATINGS** <sup>(1)</sup>

Temperature Under Bias		-65°C to +125°C
Storage Temperature		-65°C to +125°C
Surface Mount Lead Soldering Temperature	Standard Package	240°C 3 Seconds
	Lead-free Package	260°C 3 Seconds
Input Voltage with Respect to Ground on All Pins except A9 pin <sup>(2)</sup>		-0.5 V to $V_{CC} + 0.5$ V
Input Voltage with Respect to Ground on A9 pin <sup>(3)</sup>		-0.5 V to +13.0 V
All Output Voltage with Respect to Ground		-0.5 V to $V_{CC} + 0.5$ V
$V_{CC}$ <sup>(2)</sup>		-0.5 V to +6.0 V

**Notes:**

1. Stresses under those listed in “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only. The functional operation of the device or any other conditions under those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating condition for extended periods may affected device reliability.
2. Maximum DC voltage on input or I/O pins are  $V_{CC} + 0.5$  V. During voltage transitioning period, input or I/O pins may overshoot to  $V_{CC} + 2.0$  V for a period of time up to 20 ns. Minimum DC voltage on input or I/O pins are -0.5 V. During voltage transitioning period, input or I/O pins may undershoot GND to -2.0 V for a period of time up to 20 ns.
3. Maximum DC voltage on A9 pin is +13.0 V. During voltage transitioning period, A9 pin may overshoot to +14.0 V for a period of time up to 20 ns. Minimum DC voltage on A9 pin is -0.5 V. During voltage transitioning period, A9 pin may undershoot GND to -2.0 V for a period of time up to 20 ns.

**DC AND AC OPERATING RANGE**

Part Number	Pm39LV512/010/020/040
Operating Temperature	0°C to +85°C
Vcc Power Supply	2.7 V - 3.6 V

**DC CHARACTERISTICS**

Symbol	Parameter	Condition	Min	Typ	Max	Units
$I_{LI}$	Input Load Current	$V_{IN} = 0\text{ V to }V_{CC}$			1	$\mu\text{A}$
$I_{LO}$	Output Leakage Current	$V_{IO} = 0\text{ V to }V_{CC}$			1	$\mu\text{A}$
$I_{SB1}$	$V_{CC}$ Standby Current CMOS	$CE\#, OE\# = V_{CC} \pm 0.3\text{ V}$		0.1	5	$\mu\text{A}$
$I_{SB2}$	$V_{CC}$ Standby Current TTL	$CE\# = V_{IH}\text{ to }V_{CC}$		0.05	3	mA
$I_{CC1}$	$V_{CC}$ Active Read Current	$f = 5\text{ MHz}; I_{OUT} = 0\text{ mA}$		4	15	mA
$I_{CC2}^{(1)}$	$V_{CC}$ Program/Erase Current			8	20	mA
$V_{IL}$	Input Low Voltage		-0.5		0.8	V
$V_{IH}$	Input High Voltage		$0.7 V_{CC}$		$V_{CC} + 0.3$	V
$V_{OL}$	Output Low Voltage	$I_{OL} = 2.1\text{ mA}; V_{CC} = V_{CC}\text{ min}$			0.45	V
$V_{OH}$	Output High Voltage	$I_{OH} = -100\ \mu\text{A}; V_{CC} = V_{CC}\text{ min}$	$V_{CC} - 0.2$			V

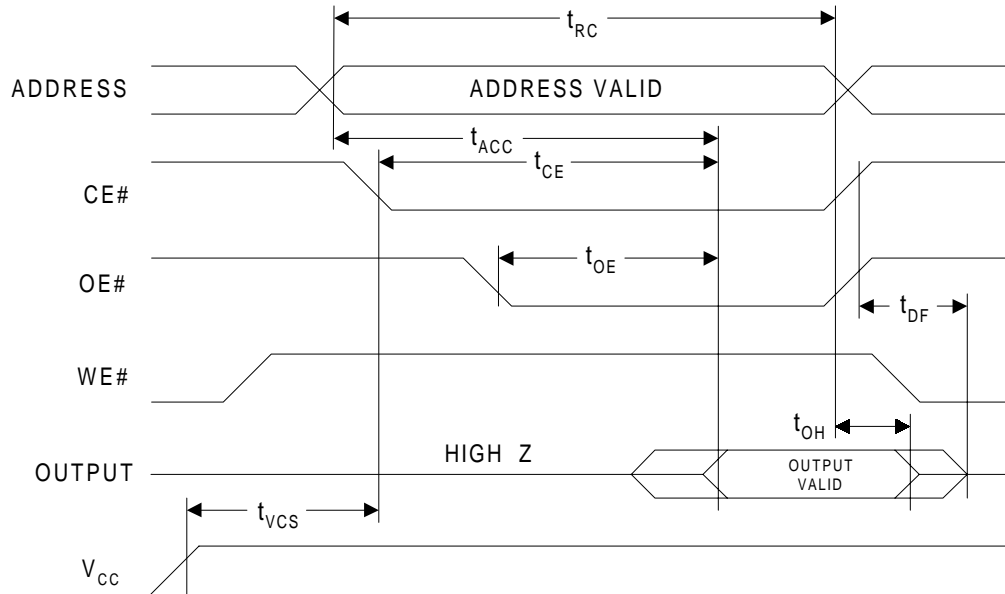
Note: 1. Characterized but not 100% tested.

**AC CHARACTERISTICS**
**READ OPERATIONS CHARACTERISTICS**

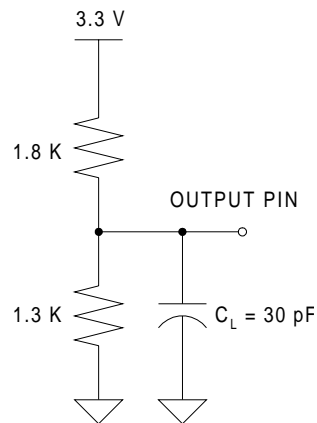
Symbol	Parameter	Pm39LV512-55 Pm39LV010-55 Pm39LV020-55 Pm39LV040-55		Pm39LV512-70 Pm39LV010-70 Pm39LV020-70 Pm39LV040-70		Units
		Min	Max	Min	Max	
$t_{RC}$	Read Cycle Time	55		70		ns
$t_{ACC}$	Address to Output Delay		55		70	ns
$t_{CE}$	CE# to Output Delay		55		70	ns
$t_{OE}$	OE# to Output Delay		30		35	ns
$t_{DF}$	CE# or OE# to Output High Z	0	15	0	25	ns
$t_{OH}$	Output Hold from OE#, CE# or Address, whichever occurred first	0		0		ns
$t_{VCS}$	$V_{CC}$ Set-up Time	50		50		$\mu\text{s}$

**AC CHARACTERISTICS (CONTINUED)**

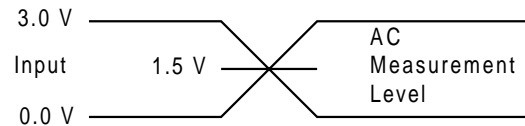
**READ OPERATIONS AC WAVEFORMS**



**OUTPUT TEST LOAD**



**INPUT TEST WAVEFORMS AND MEASUREMENT LEVEL**



**PIN CAPACITANCE ( f = 1 MHz, T = 25°C )**

	Typ	Max	Units	Conditions
$C_{IN}$	4	6	pF	$V_{IN} = 0$ V
$C_{OUT}$	8	12	pF	$V_{OUT} = 0$ V

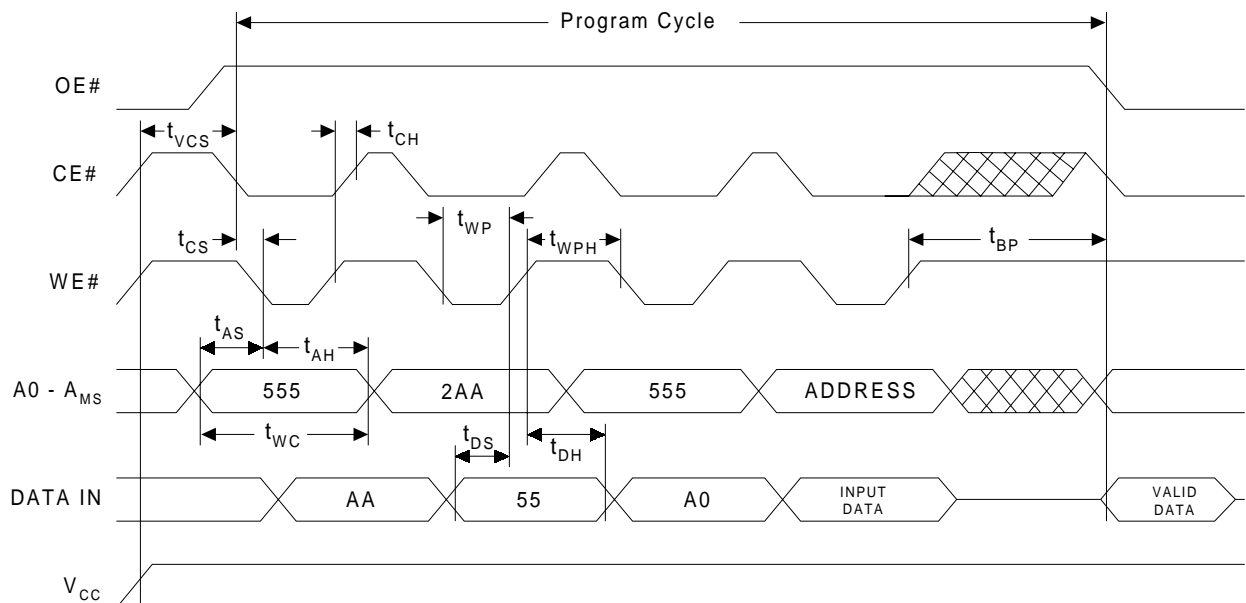
Note: These parameters are characterized but not 100% tested.

**AC CHARACTERISTICS (CONTINUED)**

**WRITE (PROGRAM/ERASE) OPERATIONS CHARACTERISTICS**

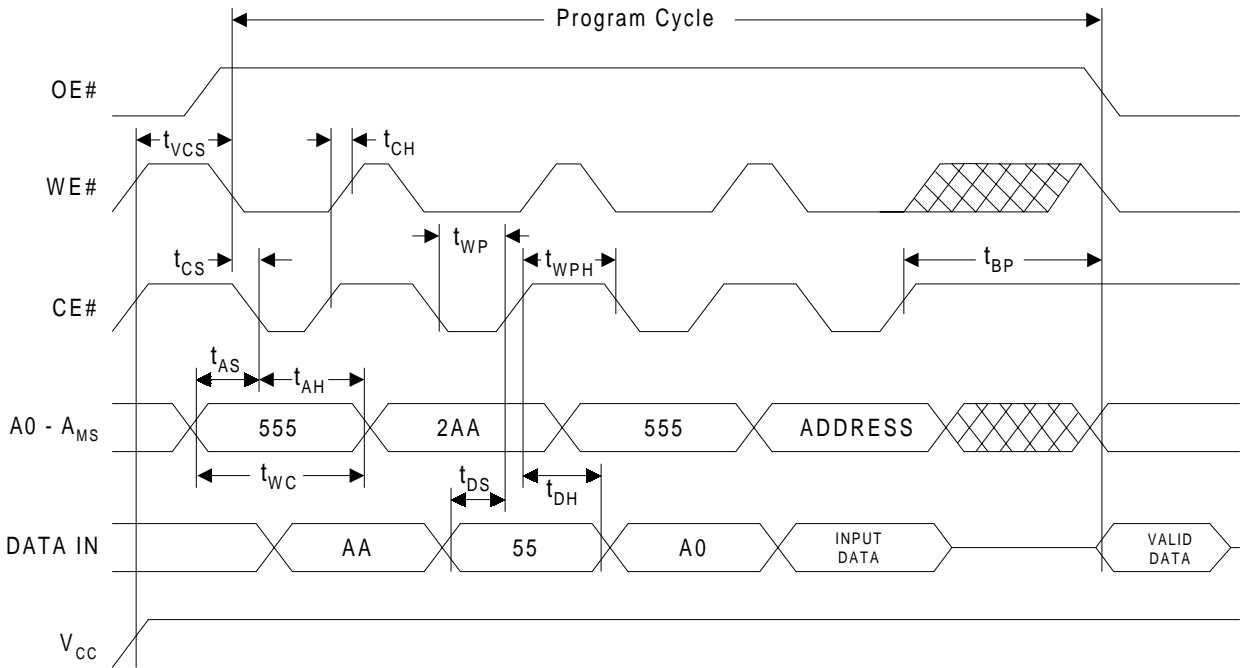
Symbol	Parameter	Pm39LV512-55 Pm39LV010-55 Pm39LV020-55 Pm39LV040-55		Pm39LV512-70 Pm39LV010-70 Pm39LV020-70 Pm39LV040-70		Units
		Min	Max	Min	Max	
$t_{WC}$	Write Cycle Time	55		70		ns
$t_{AS}$	Address Set-up Time	0		0		ns
$t_{AH}$	Address Hold Time	30		30		ns
$t_{CS}$	CE# and WE# Set-up Time	0		0		ns
$t_{CH}$	CE# and WE# Hold Time	0		0		ns
$t_{OEH}$	OE# High Hold Time	10		10		ns
$t_{DS}$	Data Set-up Time	40		40		ns
$t_{DH}$	Data Hold Time	0		0		ns
$t_{WP}$	Write Pulse Width	35		35		ns
$t_{WPH}$	Write Pulse Width High	20		20		ns
$t_{BP}$	Byte Programming Time		20		20	$\mu$ s
$t_{EC}$	Chip or Block Erase Time		100		100	ms
$t_{VCS}$	$V_{CC}$ Set-up Time	50		50		$\mu$ s

**PROGRAM OPERATIONS AC WAVEFORMS - WE# CONTROLLED**

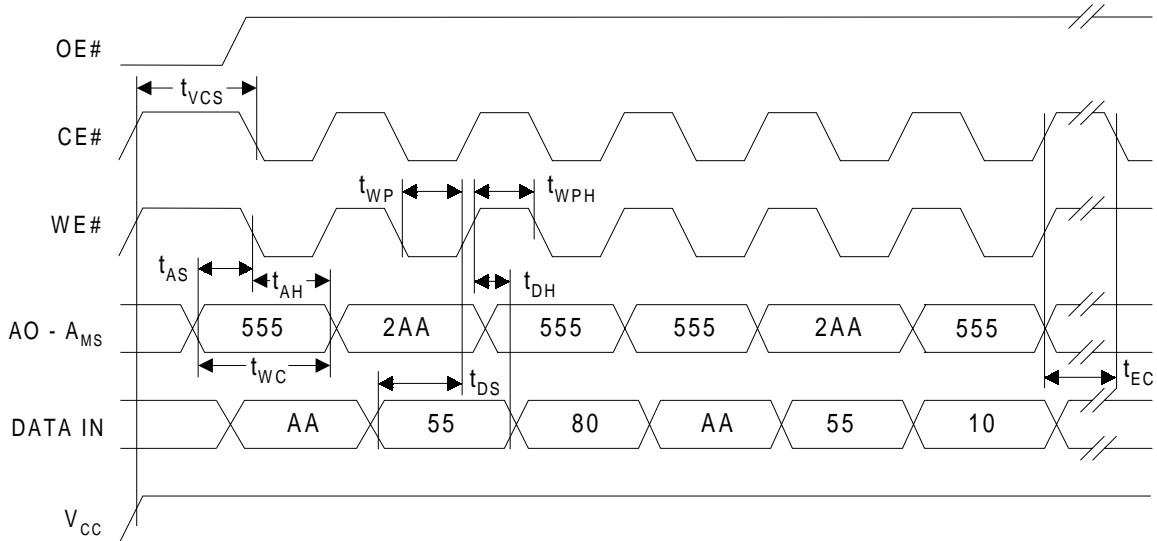


**AC CHARACTERISTICS (CONTINUED)**

**PROGRAM OPERATIONS AC WAVEFORMS - CE# CONTROLLED**



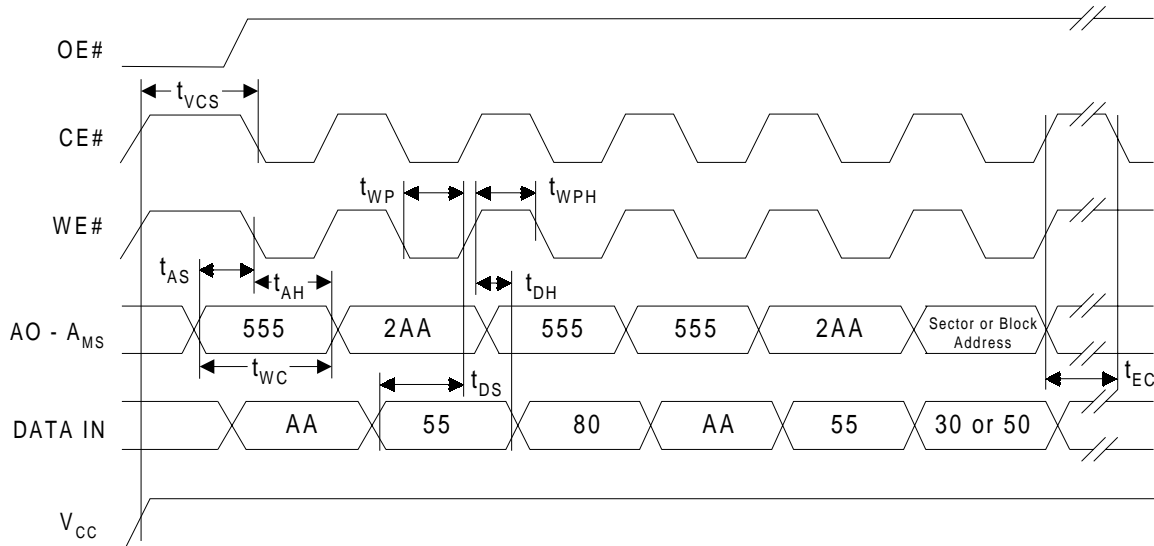
**CHIP ERASE OPERATIONS AC WAVEFORMS**



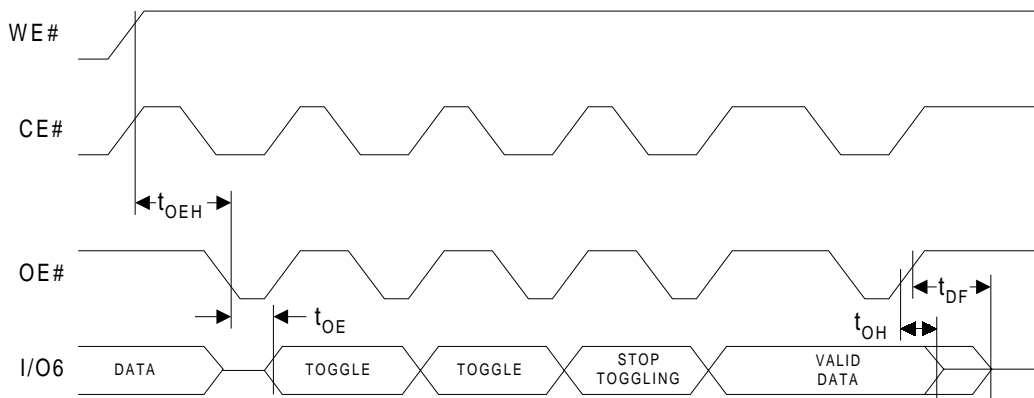


**AC CHARACTERISTICS (CONTINUED)**

**SECTOR OR BLOCK ERASE OPERATIONS AC WAVEFORMS**



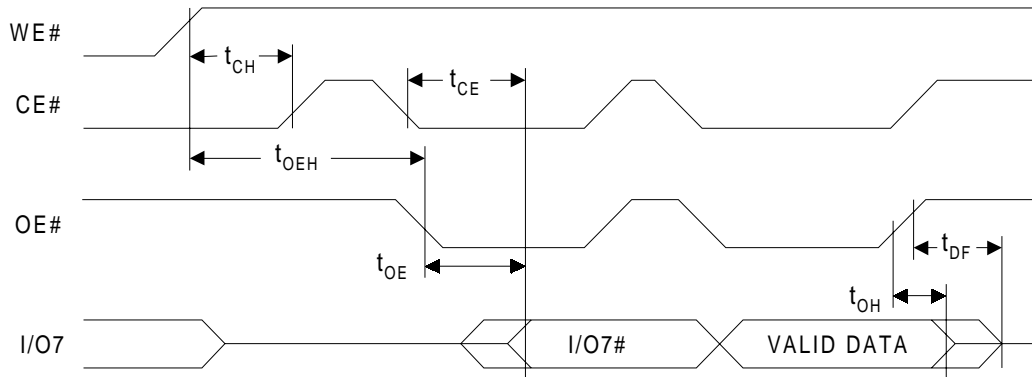
**TOGGLE BIT AC WAVEFORMS**



Note: Toggling CE#, OE#, or both OE# and CE# will operate Toggle Bit.

## AC CHARACTERISTICS (CONTINUED)

### DATA# POLLING AC WAVEFORMS



Note: Toggling CE#, OE#, or both OE# and CE# will operate Data# Polling.

## PROGRAM/ERASE PERFORMANCE

Parameter	Unit	Typ	Max	Remarks
Sector Erase Time	ms	55	100	From writing erase command to erase completion
Block Erase Time	ms	55	100	From writing erase command to erase completion
Chip Erase Time	ms	55	100	From writing erase command to erase completion
Byte Programming Time	μs	16	20	Excludes the time of four-cycle program command execution

Note: These parameters are characterized but not 100% tested.

## RELIABILITY CHARACTERISTICS <sup>(1)</sup>

Parameter	Min	Typ	Unit	Test Method
Endurance	100,000 <sup>(2)</sup>		Cycles	JEDEC Standard A117
Data Retention	20		Years	JEDEC Standard A103
ESD - Human Body Model	2,000		Volts	JEDEC Standard A114
ESD - Machine Model	200		Volts	JEDEC Standard A115
Latch-Up	100 + I <sub>CC1</sub>		mA	JEDEC Standard 78

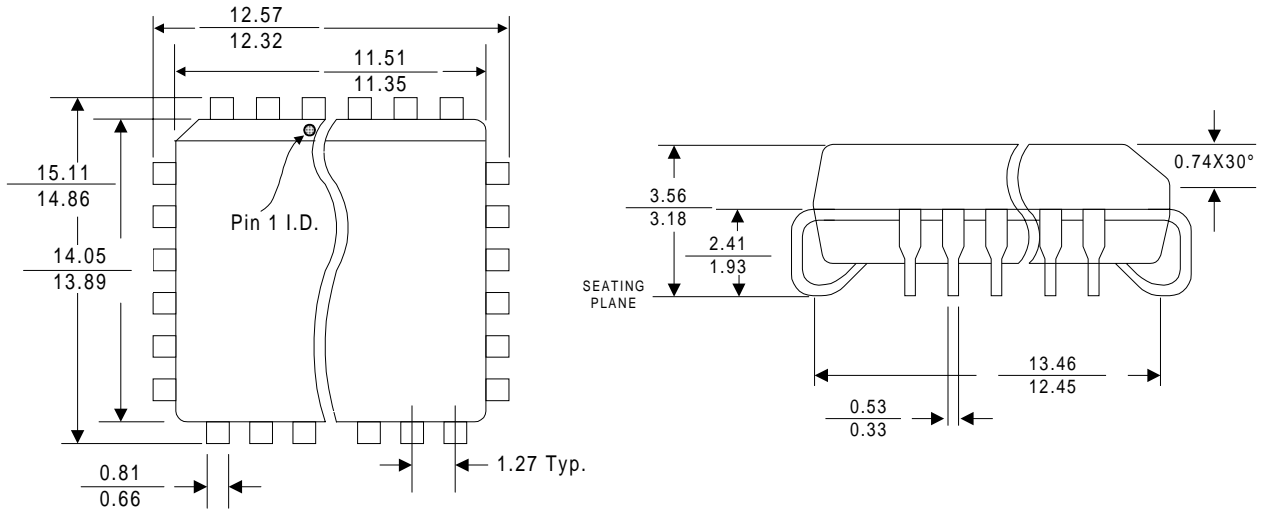
Note: 1. These parameters are characterized but not 100% tested.

2. Preliminary specification only and will be formalized after cycling qualification test.

**PACKAGE TYPE INFORMATION**

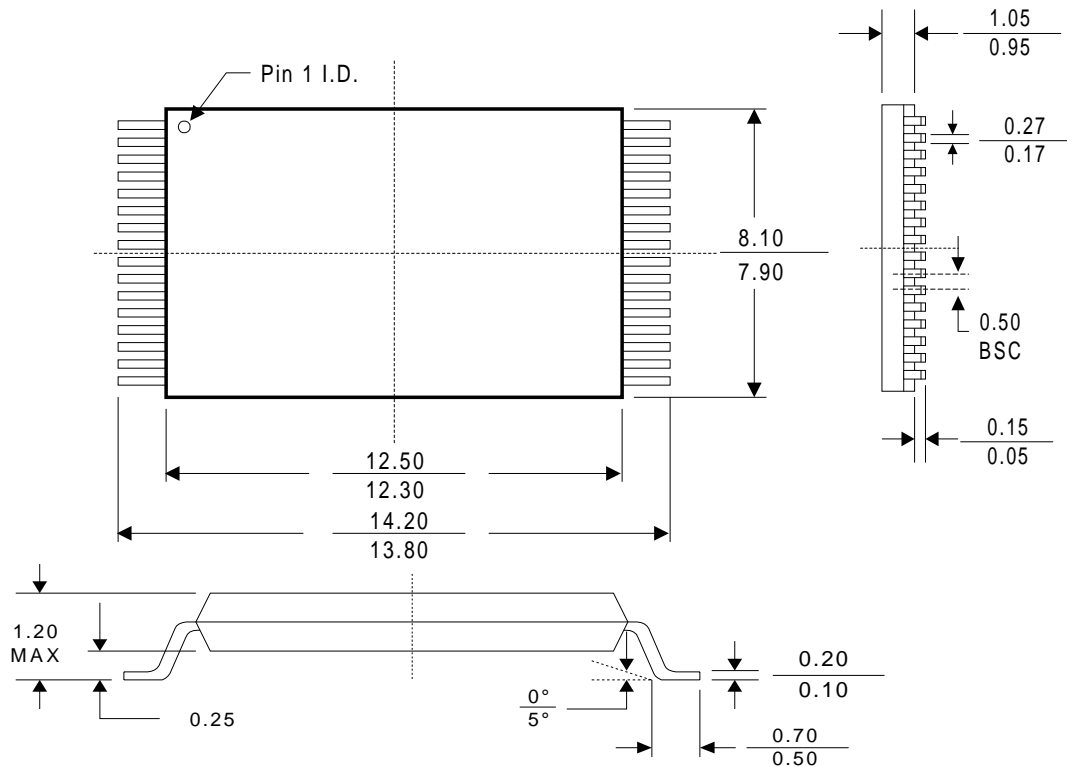
**32J**

**32-Pin Plastic Leaded Chip Carrier Dimensions in Inches (Millimeters)**



**32V**

**32-Pin Thin Small Outline Package (VSOP - 8 mm x 14 mm)( measure in millimeters)**



**REVISION HISTORY**

<b>Date</b>	<b>Revision No.</b>	<b>Description of Changes</b>	<b>Page No.</b>
May, 2003	1.0	Preliminary Information	All
September, 2003	1.1	Updated program description and formal release	5
December, 2003	1.2	Added Lead-free package option	1, 3, 12
		Upgraded guaranteed program/erase cycles from 50,000 to 100,000 (preliminary)	1, 18
		Revised output test load as 30 pF for all speed	14
		Revised package dimension information	19
March, 2004	1.3	Extend the operation range of temperature	All
June, 2005	1.4	Improve tBP (max) from 30us to 20us	15, 18
March, 2006	1.5	Change Logo and company name	All
April, 2006	1.6	Correct logo for some description	3, 5